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Please note: As part of the Fairchild Semiconductor integration, some of the Fairchild orderable part numbers will need to change in order to meet ON Semiconductor's system requirements. Since the ON Semiconductor product management systems do not have the ability to manage part nomenclature that utilizes an underscore (_), the underscore (_) in the Fairchild part numbers will be changed to a dash (-). This document may contain device numbers with an underscore (_). Please check the ON Semiconductor website to verify the updated device numbers. The most current and up-to-date ordering information can be found at www.onsemi.com. Please email any questions regarding the system integration to Fairchild_questions@onsemi.com.

September 2016

FDMS10C4D2N

N-Channel Shielded Gate PowerTrench® MOSFET

100 V, 124 A, 4.2 mΩ

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)}$ = 4.2 mΩ at V_{GS} = 10 V, I_D = 44 A
- Max $r_{DS(on)}$ = 14 mΩ at V_{GS} = 6 V, I_D = 22 A
- ADD
- 50% lower Qrr than other MOSFET suppliers
- Lowers switching noise/EMI
- MSL1 robust package design
- 100% UIL tested
- RoHS Compliant

General Description

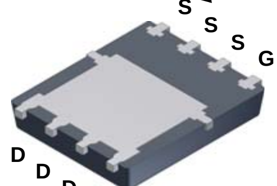
This N-Channel MV MOSFET is produced using Fairchild Semiconductor’s advanced PowerTrench® process that incorporates Shielded Gate technology. This process has been optimized to minimise on-state resistance and yet maintain superior switching performance with best in class soft body diode.

Applications

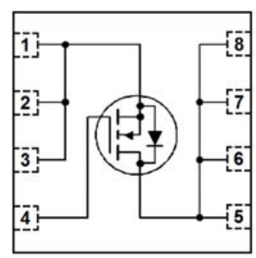
- Industrial Motor Drive
- Industrial Power Supply
- Industrial Automation
- Battery Operated Tools
- Battery Protection
- Solar Inverters
- UPS and Energy Inverters
- Energy Storage
- Load Switch

Top

Bottom



Power 56



MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units
V_{DS}	Drain to Source Voltage			100	V
V_{GS}	Gate to Source Voltage			±20	V
I_D	Drain Current -Continuous	T_C = 25 °C	(Note 5)	124	A
	-Continuous	T_C = 100 °C	(Note 5)	78	
	-Continuous	T_A = 25 °C	(Note 1a)	17	
	-Pulsed		(Note 4)	510	
E_{AS}	Single Pulse Avalanche Energy		(Note 3)	337	mJ
P_D	Power Dissipation	T_C = 25 °C		125	W
	Power Dissipation	T_A = 25 °C	(Note 1a)	2.5	
T_J, T_{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case		1.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS10C4D2N	FDMS10C4D2N	Power 56	13 ”	12 mm	3000 units

Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units

Off Characteristics

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = 250 μA, V_{GS} = 0 V	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C		60		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 80 V, V_{GS} = 0 V			1	μA
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±20 V, V_{DS} = 0 V			100	nA

On Characteristics

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
$V_{GS(th)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = 250 μA	2.0	3.1	4.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C		-9		mV/°C
$r_{DS(on)}$	Static Drain to Source On Resistance	V_{GS} = 10 V, I_D = 44 A		3.3	4.2	mΩ
		V_{GS} = 6 V, I_D = 22 A		5.3	14	
		V_{GS} = 10 V, I_D = 44 A, T_J = 125 °C		5.7	9.0	
g_{FS}	Forward Transconductance	V_{DS} = 10 V, I_D = 44 A		116		S

Dynamic Characteristics

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
C_{iss}	Input Capacitance	V_{DS} = 50 V, V_{GS} = 0 V, f = 1 MHz		2945	4500	pF
C_{oss}	Output Capacitance			1730	2600	pF
C_{rss}	Reverse Transfer Capacitance			20	50	pF
R_g	Gate Resistance		0.1	1.3	2.6	Ω

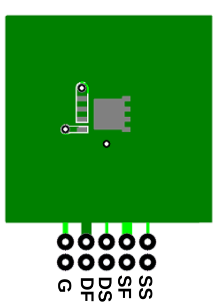
Switching Characteristics

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = 50 V, I_D = 44 A, V_{GS} = 10 V, R_{GEN} = 6 Ω		17	31	ns
t_r	Rise Time			9	18	ns
$t_{d(off)}$	Turn-Off Delay Time			25	40	ns
t_f	Fall Time			6	12	ns
Q_g	Total Gate Charge	V_{GS} = 0 V to 10 V; V_{DD} = 50 V, I_D = 44 A		42	65	nC
Q_g	Total Gate Charge	V_{GS} = 0 V to 6 V; V_{DD} = 50 V, I_D = 44 A		27	43	nC
Q_{gs}	Gate to Source Charge	V_{DD} = 50 V, I_D = 44 A		13		nC
Q_{gd}	Gate to Drain "Miller" Charge			9.3		nC

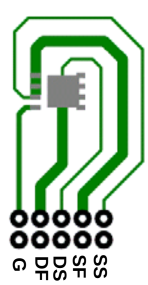
Drain-Source Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
V_{SD}	Source to Drain Diode Forward Voltage	V_{GS} = 0 V, I_S = 2.1 A (Note 2)		0.7	1.2	V
		V_{GS} = 0 V, I_S = 44 A (Note 2)		0.8	1.3	
t_{rr}	Reverse Recovery Time	I_F = 20 A, di/dt = 300 A/μs		32	52	ns
Q_{rr}	Reverse Recovery Charge			57	92	nC
t_{rr}	Reverse Recovery Time	I_F = 20 A, di/dt = 1000 A/μs		25	40	ns
Q_{rr}	Reverse Recovery Charge			158	253	nC

Notes:
1. $R_{\theta JA}$ is determined with the device mounted on a 1 in^2 pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta CA}$ is determined by the user's board design.



a) 50 °C/W when mounted on a 1 in^2 pad of 2 oz copper



b) 125 °C/W when mounted on a minimum pad of 2 oz copper.

2. Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.
3. E_{AS} of 337 mJ is based on starting T_J = 25 °C; N-ch: L = 3 mH, I_{AS} = 15 A, V_{DD} = 100 V, V_{GS} =10 V. 100% test at L = 0.1 mH, I_{AS} = 49 A.
4. Pulsed Id please refer to Fig 11 SOA graph for more details.
5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

Typical Characteristics T_J = 25 °C unless otherwise noted

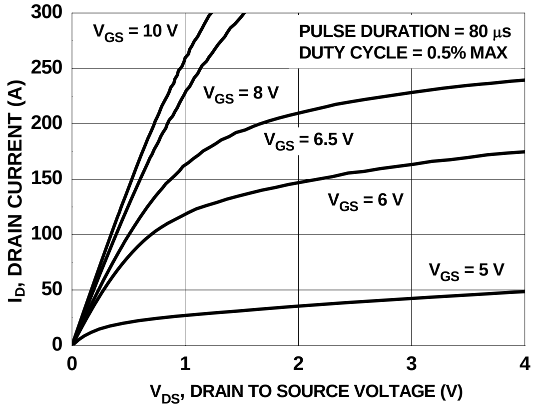


Figure 1. On-Region Characteristics

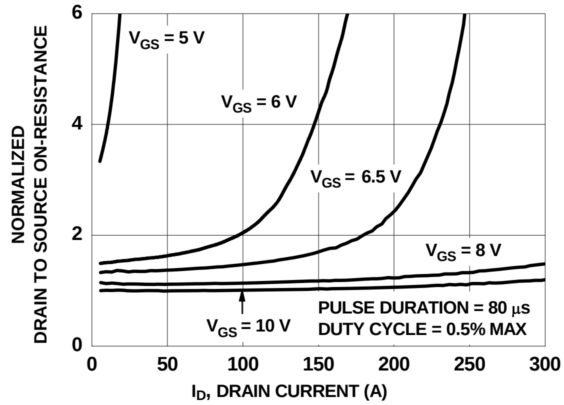


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

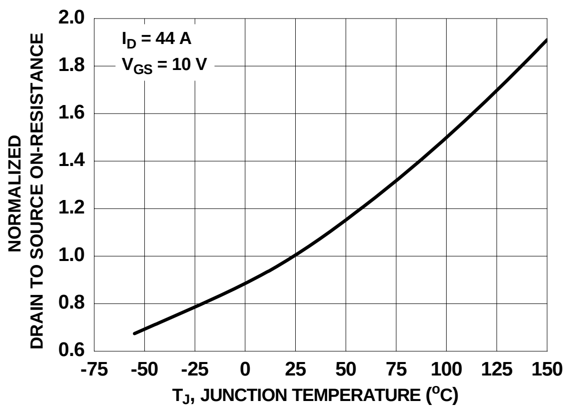


Figure 3. Normalized On-Resistance vs Junction Temperature

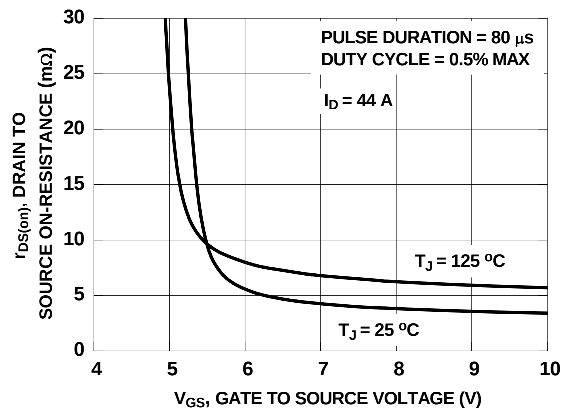


Figure 4. On-Resistance vs Gate to Source Voltage

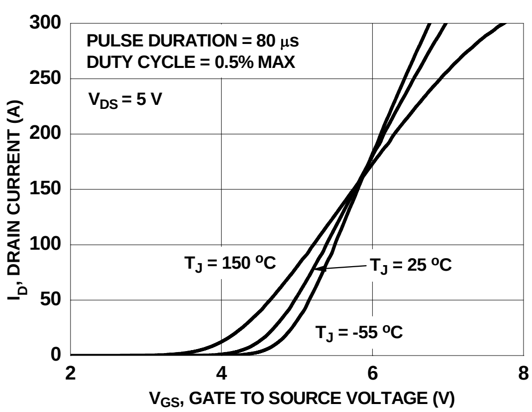


Figure 5. Transfer Characteristics

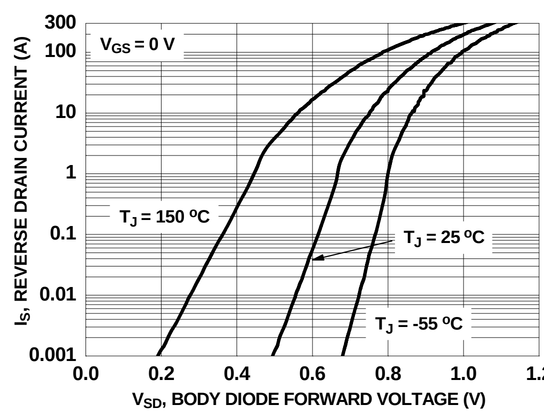


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25 °C unless otherwise noted

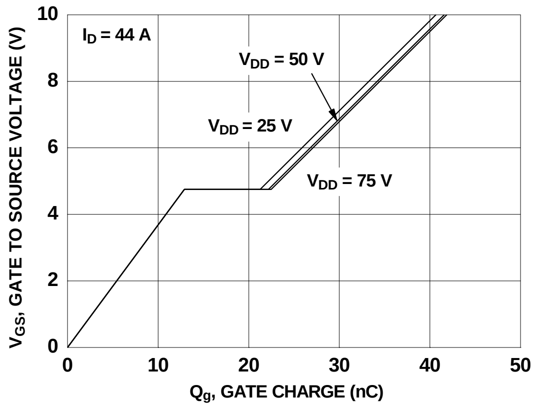


Figure 7. Gate Charge Characteristics

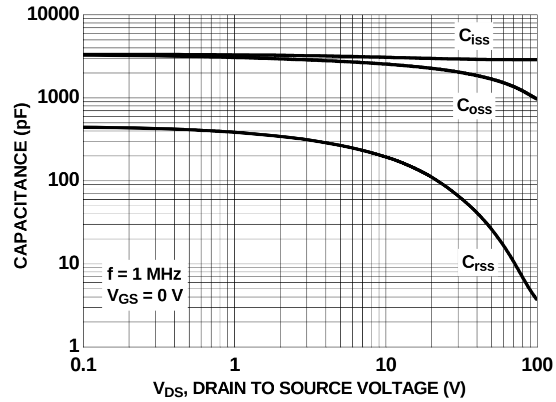


Figure 8. Capacitance vs Drain to Source Voltage

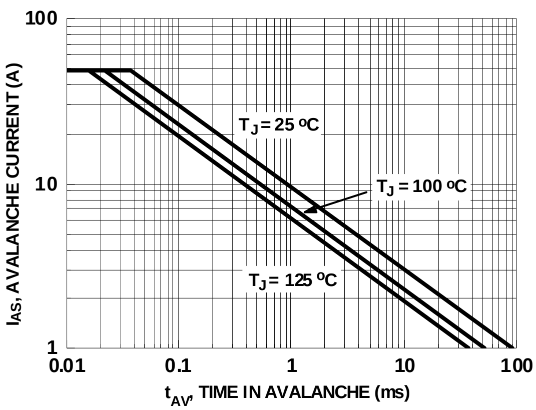


Figure 9. Unclamped Inductive Switching Capability

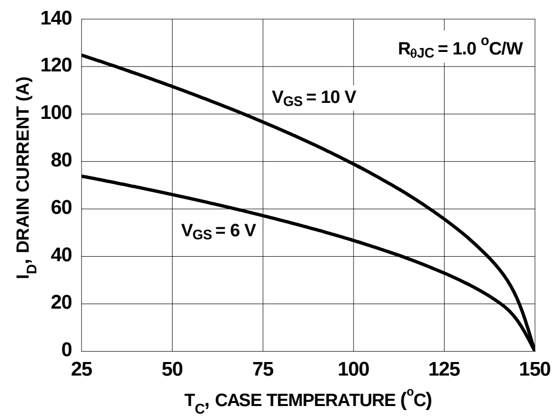


Figure 10. Maximum Continuous Drain Current vs Case Temperature

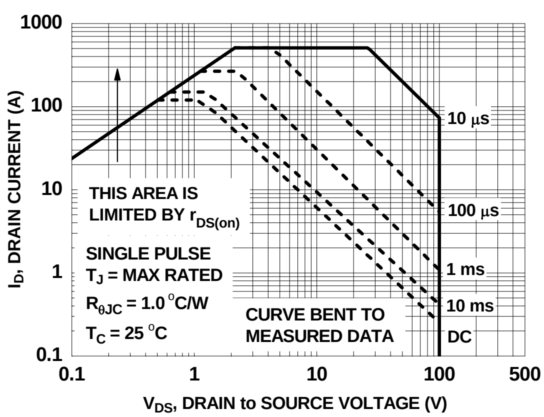


Figure 11. Forward Bias Safe Operating Area

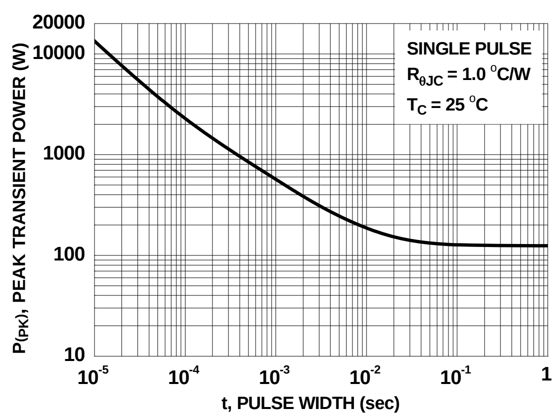


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25 °C unless otherwise noted

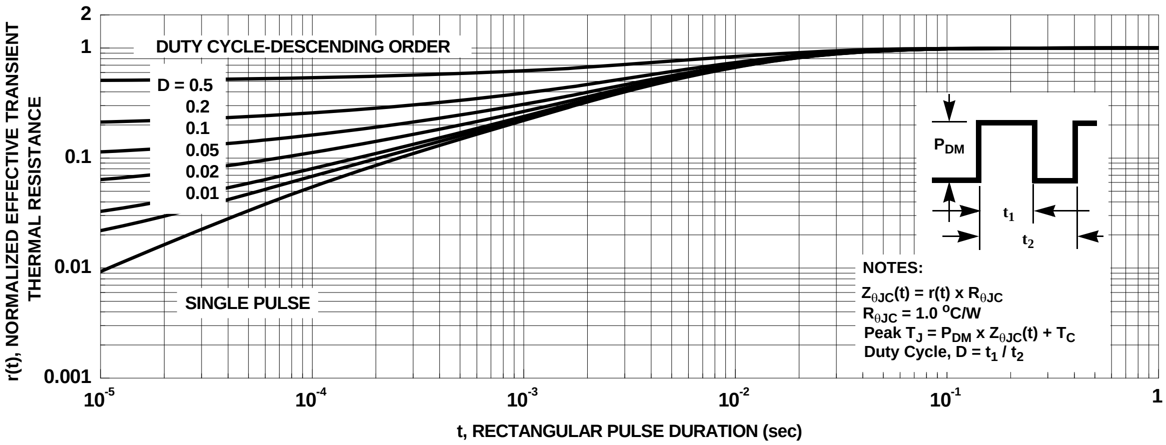
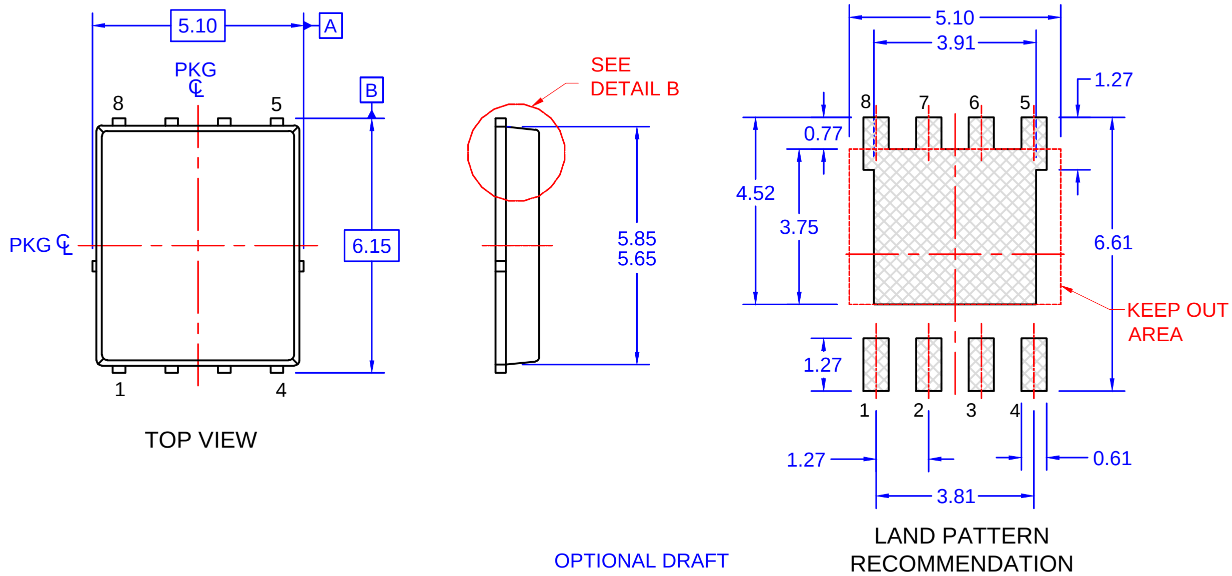
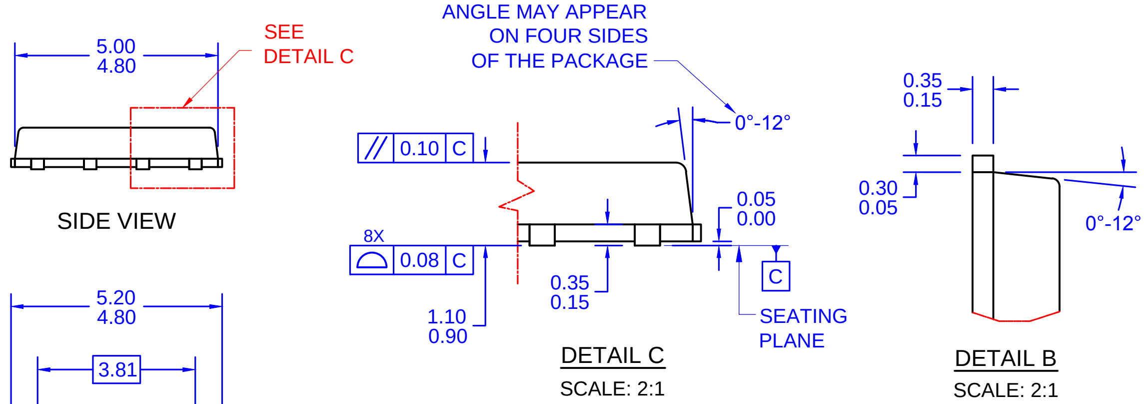
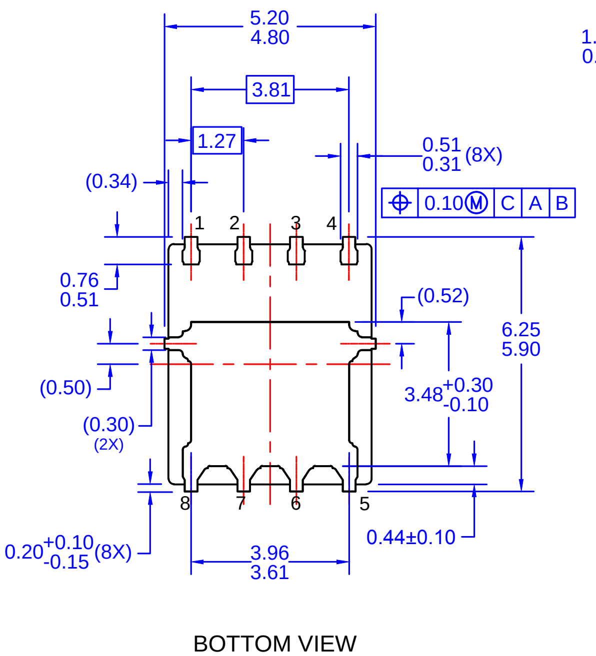


Figure 13. Junction-to-Case Transient Thermal Response Curve

PQFN8 5X6, 1.27P
CASE 483AE
ISSUE A







NOTES: UNLESS OTHERWISE SPECIFIED

A. PACKAGE STANDARD REFERENCE: JEDEC MO-240, ISSUE A, VAR. AA,.
B. DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
C. ALL DIMENSIONS ARE IN MILLIMETERS.
D. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-2009.
E. IT IS RECOMMENDED TO HAVE NO TRACES OR VIAS WITHIN THE KEEP OUT AREA.

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